FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. 59165-298553	APPLN. NO. 10/717,386 ~~Not yet known~~
	APPLICANT: NARAIN et al.	
	FILING DATE ~~Herewith~~ 11/18/03	GROUP 2825 ~~Not yet known~~

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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		5,774,370	06-30-1998	Giomi	716	4	
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VS		6,182,268	01-30-2001	McElvain	716	1	

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NUMBER	PUBLISHED DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	TRANSLATION NO
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EXAMINER	DATE CONSIDERED
VUTHE SIEK	4/06/06

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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PTO/SB/08b (05-03)
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet | 1 | of | 1

Complete if Known	
Application Number	10/717,386
Filing Date	November 18, 2003
First Named Inventor	Prakash Narain et al.
Art Unit	2825
Examiner Name	~~Not yet known~~ SIEK, V.
Attorney Docket Number	59165-298553

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials *	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[2]
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Examiner Signature	VUTHE SIEK	Date Considered	4/06/06

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